Applicant(s)/Patent Under Application/Control No. Reexamination 10/663,575 AGRAWAL ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2824 VanThu Nguyen **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY 365/230.08 US-6,631,094 B2 10-2003 Ikeda, Hitoshi Α US-6,603,817 B1 08-2003 Hamamoto et al. 375/257 В US-С D US-US-E US-F US-G US-Н US-US-J US-K US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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